In the Claims:

The following is a list of claims pending in this application and their current status. This listing replaces all prior versions and listings.

- 1. (Original) An immersion lithographic system for patterning a work piece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, comprising:
- a source emitting electromagnetic radiation onto an object plane,
- a modulator, adapted to receive and modulate said electromagnetic radiation at said object plane in accordance to an input pattern description, and to relay said electromagnetic radiation toward said work piece,
- an immersion medium contacting at least a portion of an immersion optics of said lithographic system and a portion of said work piece, wherein said immersion medium is supplied through at least one orifice arranged in said immersion optic.
- 2. (Original) The apparatus according to claim 1, wherein said modulator is an SLM.
- (Original) The apparatus according to claim 2, wherein said SLM comprises reflective pixels.
- 4. (Original) The apparatus according to claim 3, wherein said reflective pixels are micromirrors.
- 5. (Original) The apparatus according to claim 1, wherein said modulator is a acoustooptical modulator.
- 6. (Original) The apparatus according to claim 1, wherein said source emitting electromagnetic radiation is an excimer laser.
- 7. (Original) The apparatus according to claim 1, further comprising a porous or fibrous material through which said immersion medium is supplied.
- 8. (Original) The apparatus according to claim 1, further comprising at least one immersion medium removal orifice.

9. (Original) The apparatus according to claim 8, further comprising a porous or fibrous material through which said immersion medium is removed.

- 10. (Original) The apparatus according to claim 7 or 9, wherein said at porous material is kept incompletely saturated with said immersion medium.
- 11. (Original) An immersion lithographic system for patterning a work piece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, comprising
- a source emitting electromagnetic radiation onto an object plane,
- a mask arranged at said object plane to relay sald electromagnetic radiation toward said work piece,
- an immersion medium contacting at least a portion of an immersion optics of said lithographic system and a portion of said work piece, wherein said immersion medium is supplied through at least one orifice arranged in said immersion optics.
- 12. (Original) The apparatus according to claim 11, wherein said source emitting electromagnetic radiation is an excimer laser.
- 13. (Original) The apparatus according to claim 11, further comprising a porous or fibrous material through which said immersion medium is supplied.
- 14. (Original) The apparatus according to claim 11, further comprising at least one immersion medium removal orifice.
- 15. (Original) The apparatus according to claim 14, further comprising a porous or fibrous material through which said immersion medium is removed.
- 16. (Original) The apparatus according to claim 13 or 15, wherein said at porous or fibrous material is kept incompletely saturated with said immersion medium.
- 17. (Original) An immersion lithographic system for patterning a work piece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, comprising
- a source emitting electromagnetic radiation onto an object plane,
- a modulator, adapted to receive and modulate said electromagnetic radiation at

said object plane in accordance to an input pattern description and to relay said electromagnetic radiation toward said work piece,

- an immersion medium contacting at least a portion of a objective lens of said lithographic system and a portion of said work piece, wherein an area of said contacting is restricted by capillary forces.
- 18. (Original) The immersion lithography system according to claim 17, further comprising a immersion medium reservoir for supplying immersion medium to said portion of said objective lens and said workpiece.
- 19. (Original) The immersion lithography system according to claim 18, wherein said immersion medium is supplied through a porous or fibrous material.
- 20. (Original) An immersion lithographic system for patterning a work piece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, comprising
- a source emitting electromagnetic radiation onto an object plane,
- a mask, adapted to receive and modulate said electromagnetic radiation at said object plane and to relay said electromagnetic radiation toward said work piece.
- an immersion medium contacting at least a portion of a final lens of said lithographic system and a portion of said work piece, wherein an area of said contacting is restricted by capillary forces.
- 21. (Original) The immersion lithography system according to claim 17, further comprising a immersion medium reservoir for supplying immersion medium to said portion of said objective lens and said workpiece.
- 22. (Original) The immersion lithography system according to claim 18, wherein said immersion medium is supplied through a porous or fibrous material.
- 23. (Original) A method for patterning a workpiece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, including the actions of:
- emitting electromagnetic radiation onto an object plane,

- modulating said electromagnetic radiation at said object plane in accordance to an input pattern description,

- relaying said electromagnetic radiation toward said workpiece,
- supplying an immersion medium to contact at least a portion of an objective lens of said lithographic system and at least a portion of said workpiece.
- 24. (Original) The method according to claim 23, further comprising the action of:
- restricting a lateral extension of said contact by capillary forces.
- 25. (Original) A method for patterning a workpiece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, including the actions of:
- emitting electromagnetic radiation onto an object plane,
- modulating said electromagnetic radiation at said object plane in accordance to an input pattern description,
- relaying said electromagnetic radiation toward said workpiece,
- contacting at least a portion of an objective lens of said lithographic system and at least a portion of said workpiece via a immersion medium, wherein said contacting is restricted in a lateral direction of said workpiece by capillary forces.
- 26. (Original) The method according to claim 25, further including the action of:
- supplying said immersion medium via a immersion medium reservoir.
- 27. (Original) The method according to claim 26, wherein said immersion medium is supplied through a porous or fibrous material.
- 28. (Original) A method for patterning a workpiece arranged at an image plane and covered at least partly with a layer sensitive to electromagnetic radiation, including the actions of:
- emitting electromagnetic radiation onto an object plane,
- modulating said electromagnetic radiation at said object plane in accordance to an input pattern description,

- relaying said electromagnetic radiation toward said workpiece,
- forming an immersion medium film to contact at least a portion of an objective lens of said lithographic system and at least a portion of said workpiece, supplying immersion medium to said immersion medium film to maintain its lateral dimensions while moving said objective lens over said workpiece.